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## What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

## Applications of "[Embedded - Microcontrollers](#)"

### Details

Product Status	Discontinued at Digi-Key
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	72MHz
Connectivity	I <sup>2</sup> C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	28
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x14b; D/A 4x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	32-TQFP
Supplier Device Package	32-QFP (7x7)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64e-a-qfp32r">https://www.e-xfl.com/product-detail/silicon-labs/efm8lb12f64e-a-qfp32r</a>

## 2. Ordering Information

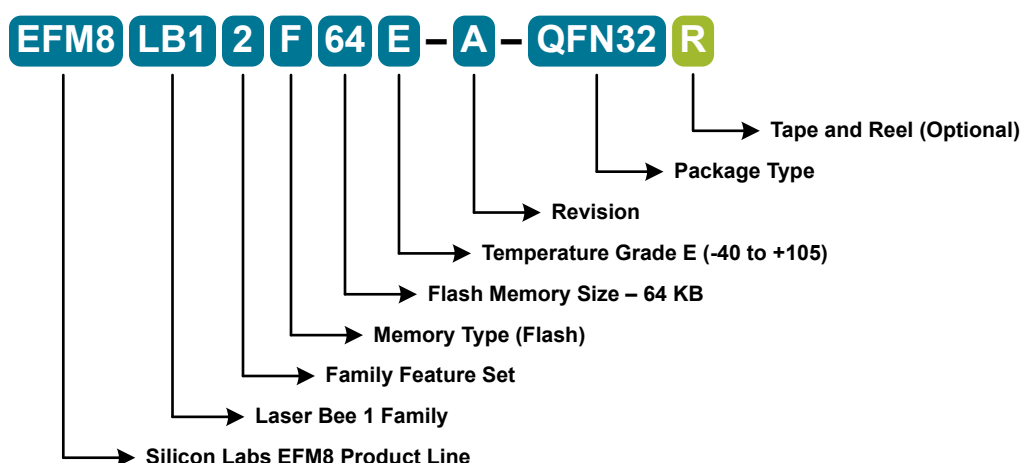


Figure 2.1. EFM8LB1 Part Numbering

All EFM8LB1 family members have the following features:

- CIP-51 Core running up to 72 MHz
- Three Internal Oscillators (72 MHz, 24.5 MHz and 80 kHz)
- SMBus
- I2C Slave
- SPI
- 2 UARTs
- 6-Channel Programmable Counter Array (PWM, Clock Generation, Capture/Compare)
- Six 16-bit Timers
- Four Configurable Logic Units
- 14-bit Analog-to-Digital Converter with integrated multiplexer, voltage reference, temperature sensor, channel sequencer, and direct-to-XXRAM data transfer
- Two Analog Comparators
- 16-bit CRC Unit
- AEC-Q100 qualified (pending)

In addition to these features, each part number in the EFM8LB1 family has a set of features that vary across the product line. The product selection guide shows the features available on each family member.

Table 2.1. Product Selection Guide

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F64E-A-QFN32	64	4352	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F64E-A-QFP32	64	4352	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F64E-A-QFN24	64	4352	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F64E-A-QSOP24	64	4352	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24

Ordering Part Number	Flash Memory (kB)	RAM (Bytes)	Digital Port I/Os (Total)	ADC0 Channels	Voltage DACs	Comparator 0 Inputs	Comparator 1 Inputs	Pb-free (RoHS Compliant)	Temperature Range	Package
EFM8LB12F32E-A-QFN32	32	2304	29	20	4	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB12F32E-A-QFP32	32	2304	28	20	4	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB12F32E-A-QFN24	32	2304	20	12	4	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB12F32E-A-QSOP24	32	2304	21	13	4	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F32E-A-QFN32	32	2304	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F32E-A-QFP32	32	2304	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F32E-A-QFN24	32	2304	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F32E-A-QSOP24	32	2304	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB11F16E-A-QFN32	16	1280	29	20	2	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB11F16E-A-QFP32	16	1280	28	20	2	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB11F16E-A-QFN24	16	1280	20	12	2	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB11F16E-A-QSOP24	16	1280	21	13	2	6	7	Yes	-40 to +105 °C	QSOP24
EFM8LB10F16E-A-QFN32	16	1280	29	20	0	10	9	Yes	-40 to +105 °C	QFN32
EFM8LB10F16E-A-QFP32	16	1280	28	20	0	10	9	Yes	-40 to +105 °C	QFP32
EFM8LB10F16E-A-QFN24	16	1280	20	12	0	6	6	Yes	-40 to +105 °C	QFN24
EFM8LB10F16E-A-QSOP24	16	1280	21	13	0	6	7	Yes	-40 to +105 °C	QSOP24

## 3. System Overview

### 3.1 Introduction

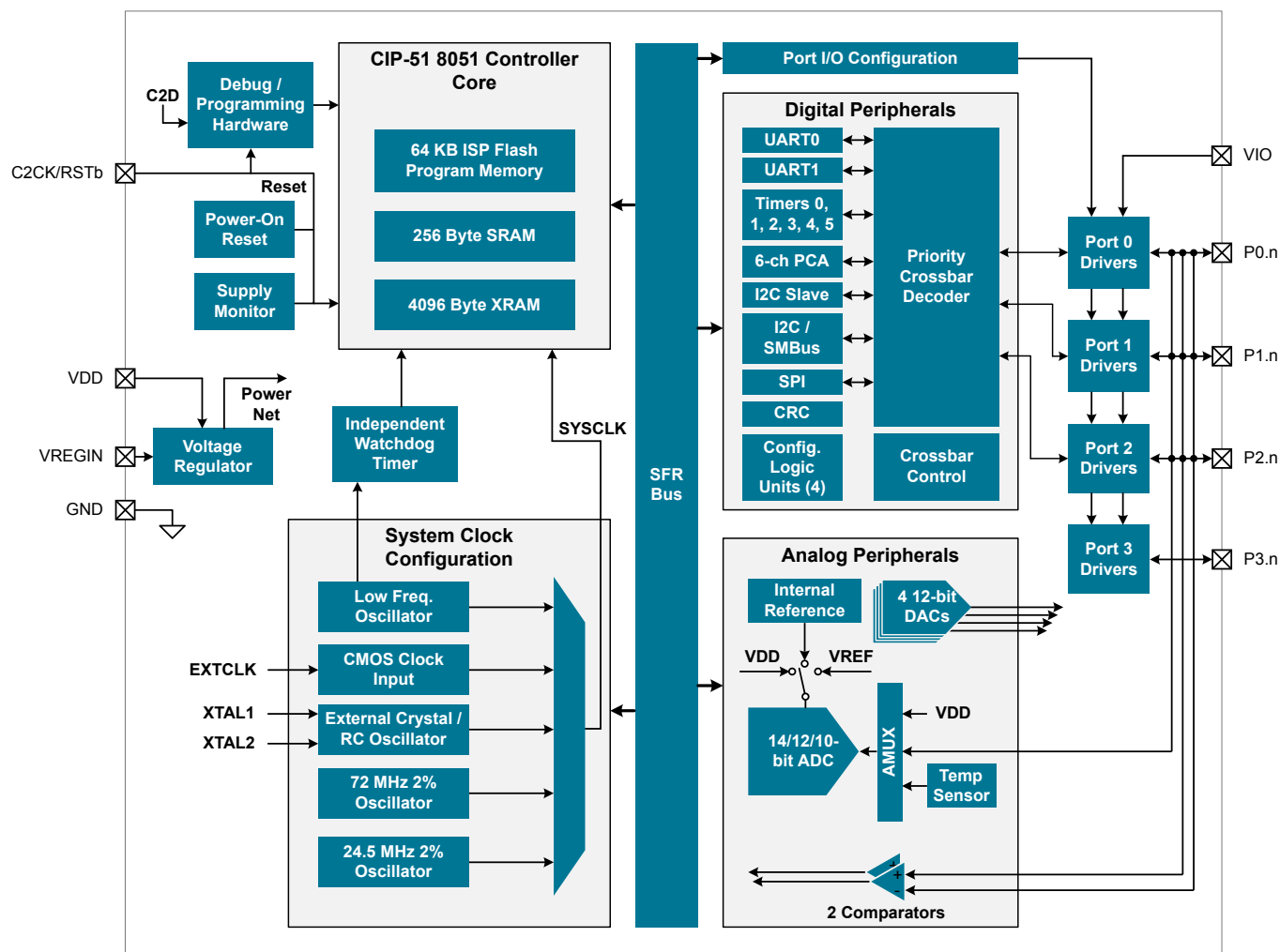


Figure 3.1. Detailed EFM8LB1 Block Diagram

## I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Hardware support for multiple slave addresses with the option to save the matching address in the receive FIFO

## 16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

## Configurable Logic Units (CLU0, CLU1, CLU2, and CLU3)

The Configurable Logic block consists of multiple Configurable Logic Units (CLUs). CLUs are flexible logic functions which may be used for a variety of digital functions, such as replacing system glue logic, aiding in the generation of special waveforms, or synchronizing system event triggers.

- Four configurable logic units (CLUs), with direct-pin and internal logic connections
- Each unit supports 256 different combinatorial logic functions (AND, OR, XOR, muxing, etc.) and includes a clocked flip-flop for synchronous operations
- Units may be operated synchronously or asynchronously
- May be cascaded together to perform more complicated logic functions
- Can operate in conjunction with serial peripherals such as UART and SPI or timing peripherals such as timers and PCA channels
- Can be used to synchronize and trigger multiple on-chip resources (ADC, DAC, Timers, etc.)
- Asynchronous output may be used to wake from low-power states

#### 4.1.4 Flash Memory

Table 4.4. Flash Memory

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Write Time <sup>1,2</sup>	$t_{\text{WRITE}}$	One Byte, $F_{\text{SYSCLK}} = 24.5 \text{ MHz}$	19	20	21	$\mu\text{s}$
Erase Time <sup>1,2</sup>	$t_{\text{ERASE}}$	One Page, $F_{\text{SYSCLK}} = 24.5 \text{ MHz}$	5.2	5.35	5.5	ms
$V_{\text{DD}}$ Voltage During Programming <sup>3</sup>	$V_{\text{PROG}}$		2.2	—	3.6	V
Endurance (Write/Erase Cycles)	$N_{\text{WE}}$		20k	100k	—	Cycles

**Note:**

1. Does not include sequencing time before and after the write/erase operation, which may be multiple SYSCLK cycles.
2. The internal High-Frequency Oscillator 0 has a programmable output frequency, which is factory programmed to 24.5 MHz. If user firmware adjusts the oscillator speed, it must be between 22 and 25 MHz during any flash write or erase operation. It is recommended to write the HFO0CAL register back to its reset value when writing or erasing flash.
3. Flash can be safely programmed at any voltage above the supply monitor threshold ( $V_{\text{VDDM}}$ ).
4. Data Retention Information is published in the Quarterly Quality and Reliability Report.

#### 4.1.5 Power Management Timing

Table 4.5. Power Management Timing

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Idle Mode Wake-up Time	$t_{\text{IDLEWK}}$		2	—	3	SYSCLKs
Suspend Mode Wake-up Time	$t_{\text{SUS-}}t_{\text{PENDWK}}$	$\text{SYSCLK} = \text{HFOSC0}$ $\text{CLKDIV} = 0x00$	—	170	—	ns
Snooze Mode Wake-up Time	$t_{\text{SLEEPWK}}$	$\text{SYSCLK} = \text{HFOSC0}$ $\text{CLKDIV} = 0x00$	—	12	—	$\mu\text{s}$

#### 4.1.10 Voltage Reference

Table 4.10. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	$V_{\text{REFFS}}$		1.62	1.65	1.68	V
Temperature Coefficient	$TC_{\text{REFFS}}$		—	50	—	ppm/°C
Turn-on Time	$t_{\text{REFFS}}$		—	—	1.5	μs
Power Supply Rejection	$PSRR_{\text{REFFS}}$		—	400	—	ppm/V
On-chip Precision Reference						
Valid Supply Range	$V_{\text{DD}}$	1.2 V Output	2.2	—	3.6	V
		2.4 V Output	2.7	—	3.6	V
Output Voltage	$V_{\text{REFP}}$	1.2 V Output, T = 25 °C	TBD	1.2	TBD	V
		2.4 V Output, T = 25 °C	TBD	2.4	TBD	V
Turn-on Time, settling to 0.5 LSB	$t_{\text{VREFP}}$	4.7 μF tantalum + 0.1 μF ceramic bypass on VREF pin	—	3	—	ms
		0.1 μF ceramic bypass on VREF pin	—	100	—	μs
Load Regulation	$LR_{\text{VREFP}}$	Load = 0 to 200 μA to GND	—	TBD	—	μV/μA
Load Capacitor	$C_{\text{VREFP}}$	Load = 0 to 200 μA to GND	0.1	—	—	μF
Short-circuit current	$ISC_{\text{VREFP}}$		—	—	8	mA
Power Supply Rejection	$PSRR_{\text{VREFP}}$		—	TBD	—	ppm/V
External Reference						
Input Current	$I_{\text{EXTREF}}$	ADC Sample Rate = 1 Msps; VREF = 3.0 V	—	5	—	μA

#### 4.1.11 Temperature Sensor

**Table 4.11. Temperature Sensor**

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Uncalibrated Offset	$V_{OFF}$	$T_A = 0\text{ }^{\circ}\text{C}$	—	TBD	—	mV
Uncalibrated Offset Error <sup>1</sup>	$E_{OFF}$	$T_A = 0\text{ }^{\circ}\text{C}$	—	TBD	—	mV
Slope	M		—	2.83	—	mV/ $^{\circ}\text{C}$
Slope Error <sup>1</sup>	$E_M$		—	TBD	—	$\mu\text{V}/^{\circ}\text{C}$
Linearity			—	TBD	—	$^{\circ}\text{C}$
Turn-on Time			—	TBD	—	$\mu\text{s}$
Temp Sensor Error Using Typical Slope and Factory-Calibrated Offset <sup>2, 3</sup>		$T = 0\text{ }^{\circ}\text{C}$ to $70\text{ }^{\circ}\text{C}$	TBD	—	TBD	$^{\circ}\text{C}$
		$T = -20\text{ }^{\circ}\text{C}$ to $85\text{ }^{\circ}\text{C}$	-3	—	3	$^{\circ}\text{C}$
		$T = -40\text{ }^{\circ}\text{C}$ to $105\text{ }^{\circ}\text{C}$	TBD	—	TBD	$^{\circ}\text{C}$

**Note:**

1. Represents one standard deviation from the mean.
2. The factory-calibrated offset value is stored in the read-only area of flash in locations 0xFFD4 (low byte) and 0xFFD5 (high byte). The 14-bit result represents the output of the ADC when sampling the temp sensor using the 1.65 V internal voltage reference.
3. Temp sensor error is based upon characterization and is not tested across temperature in production. The values represent three standard deviations above and below the mean.



#### 4.1.15 Port I/O

Table 4.15. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (High Drive)	$V_{OH}$	$I_{OH} = -7 \text{ mA}$ , $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -3.3 \text{ mA}$ , $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.8 \text{ mA}$ , $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (High Drive)	$V_{OL}$	$I_{OL} = 13.5 \text{ mA}$ , $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 7 \text{ mA}$ , $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 3.6 \text{ mA}$ , $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output High Voltage (Low Drive)	$V_{OH}$	$I_{OH} = -4.75 \text{ mA}$ , $V_{IO} \geq 3.0 \text{ V}$	$V_{IO} - 0.7$	—	—	V
		$I_{OH} = -2.25 \text{ mA}$ , $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	$V_{IO} \times 0.8$	—	—	V
		$I_{OH} = -1.2 \text{ mA}$ , $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Output Low Voltage (Low Drive)	$V_{OL}$	$I_{OL} = 6.5 \text{ mA}$ , $V_{IO} \geq 3.0 \text{ V}$	—	—	0.6	V
		$I_{OL} = 3.5 \text{ mA}$ , $2.2 \text{ V} \leq V_{IO} < 3.0 \text{ V}$	—	—	$V_{IO} \times 0.2$	V
		$I_{OL} = 1.8 \text{ mA}$ , $1.71 \text{ V} \leq V_{IO} < 2.2 \text{ V}$				
Input High Voltage	$V_{IH}$		$0.7 \times V_{IO}$	—	—	V
Input Low Voltage	$V_{IL}$		—	—	$0.3 \times V_{IO}$	V
Pin Capacitance	$C_{IO}$		—	7	—	pF
Weak Pull-Up Current ( $V_{IN} = 0 \text{ V}$ )	$I_{PU}$	$V_{DD} = 3.6$	-30	-20	-10	$\mu\text{A}$
Input Leakage (Pullups off or Analog)	$I_{LK}$	$\text{GND} < V_{IN} < V_{IO}$	TBD	—	TBD	$\mu\text{A}$
Input Leakage Current with $V_{IN}$ above $V_{IO}$	$I_{LK}$	$V_{IO} < V_{IN} < V_{IO} + 2.5 \text{ V}$ Any pin except P3.0, P3.1, P3.2, or P3.3	0	5	150	$\mu\text{A}$

## 5.2 Debug

The diagram below shows a typical connection diagram for the debug connections pins. The pin sharing resistors are only required if the functionality on the C2D (a GPIO pin) and the C2CK (RSTb) is routed to external circuitry. For example, if the RSTb pin is connected to an external switch with debouncing filter or if the GPIO sharing with the C2D pin is connected to an external circuit, the pin sharing resistors and connections to the debug adapter must be placed on the hardware. Otherwise, these components and connections can be omitted.

For more information on debug connections, see the example schematics and information available in AN127: "Pin Sharing Techniques for the C2 Interface." Application notes can be found on the Silicon Labs website (<http://www.silabs.com/8bit-appnotes>) or in Simplicity Studio.

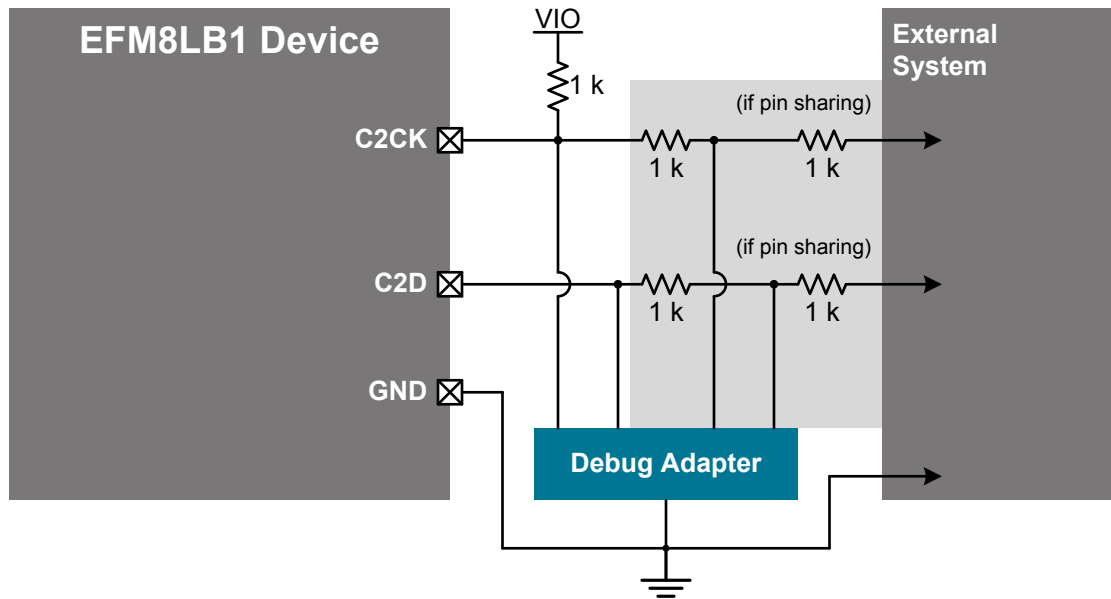


Figure 5.2. Debug Connection Diagram

## 5.3 Other Connections

Other components or connections may be required to meet the system-level requirements. Application Note AN203: "8-bit MCU Printed Circuit Board Design Notes" contains detailed information on these connections. Application Notes can be accessed on the Silicon Labs website ([www.silabs.com/8bit-appnotes](http://www.silabs.com/8bit-appnotes)).

**Table 6.1. Pin Definitions for EFM8LB1x-QFN32**

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	VIO	I/O Supply Power Input			
3	VDD	Supply Power Input			
4	RSTb / C2CK	Active-low Reset / C2 Debug Clock			
5	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
6	P3.4	Multifunction I/O			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
28	P0.5	Multifunction I/O	Yes	P0MAT.5 INT0.5 INT1.5 UART0_RX CLU0B.10 CLU1A.9	ADC0.3 CMP0P.3 CMP0N.3
29	P0.4	Multifunction I/O	Yes	P0MAT.4 INT0.4 INT1.4 UART0_TX CLU0A.10 CLU1A.8	ADC0.2 CMP0P.2 CMP0N.2
30	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2
31	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2 CLU0OUT CLU0A.9 CLU2B.8 CLU3A.8	XTAL1 ADC0.1 CMP0P.1 CMP0N.1
32	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1 CLU0B.8 CLU2A.9 CLU3B.9	ADC0.0 CMP0P.0 CMP0N.0 AGND
Center	GND	Ground			

## 6.2 EFM8LB1x-QFP32 Pin Definitions

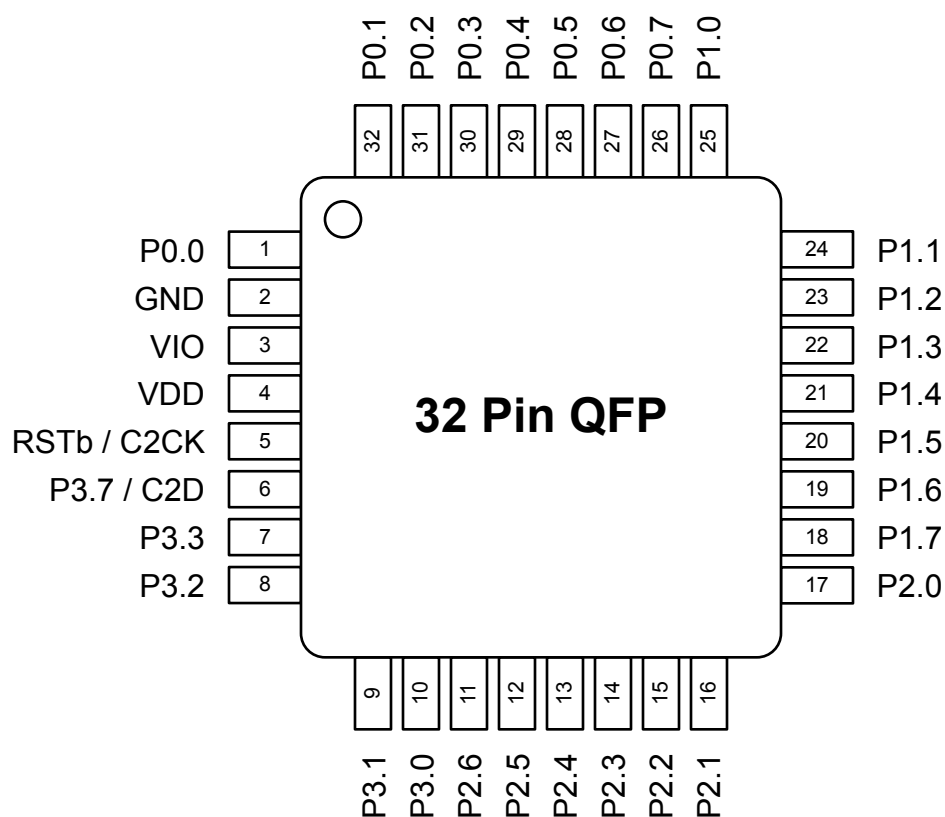


Figure 6.2. EFM8LB1x-QFP32 Pinout

Table 6.2. Pin Definitions for EFM8LB1x-QFP32

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0 CLU0A.8 CLU2A.8 CLU3B.8	VREF
2	GND	Ground			
3	VIO	I/O Supply Power Input			
4	VDD	Supply Power Input			
5	RSTb / C2CK	Active-low Reset / C2 Debug Clock			

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
12	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13 CLU3B.11	ADC0.10 CMP1P.4 CMP1N.4
13	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12 CLU3B.10	ADC0.9 CMP1P.3 CMP1N.3
14	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2
15	GND	Ground			
16	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12 CLU3B.13	ADC0.8
17	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.12	ADC0.7
18	P1.0	Multifunction I/O	Yes	P1MAT.0 CLU0A.12 CLU1A.10 CLU2A.10	ADC0.6

## 6.4 EFM8LB1x-QSOP24 Pin Definitions

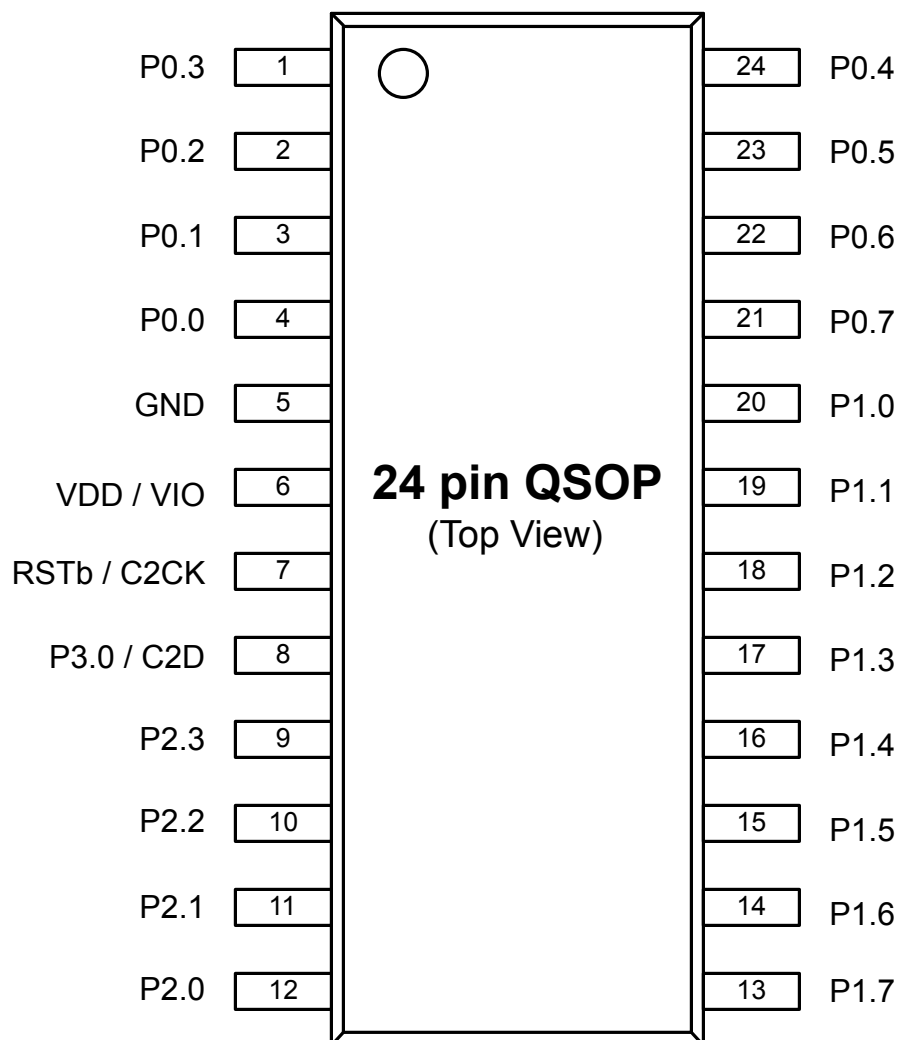


Figure 6.4. EFM8LB1x-QSOP24 Pinout

Table 6.4. Pin Definitions for EFM8LB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.3	Multifunction I/O	Yes	P0MAT.3 EXTCLK INT0.3 INT1.3 CLU0B.9 CLU2B.10 CLU3A.9	XTAL2

Dimension	Min	Typ	Max
<b>Note:</b> <ol style="list-style-type: none"> <li>1. All dimensions shown are in millimeters (mm) unless otherwise noted.</li> <li>2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.</li> <li>3. This drawing conforms to JEDEC Solid State Outline MO-220.</li> <li>4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.</li> </ol>			



Dimension	Min	Max
<b>Note:</b> <ol style="list-style-type: none"> <li>1. All dimensions shown are in millimeters (mm) unless otherwise noted.</li> <li>2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.</li> <li>3. This Land Pattern Design is based on the IPC-7351 guidelines.</li> <li>4. All dimensions shown are at Maximum Material Condition (MMC). Least Material Condition (LMC) is calculated based on a Fabrication Allowance of 0.05mm.</li> <li>5. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.</li> <li>6. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.</li> <li>7. The stencil thickness should be 0.125 mm (5 mils).</li> <li>8. The ratio of stencil aperture to land pad size should be 1:1 for all perimeter pads.</li> <li>9. A 2 x 2 array of 1.10 mm square openings on a 1.30 mm pitch should be used for the center pad.</li> <li>10. A No-Clean, Type-3 solder paste is recommended.</li> <li>11. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.</li> </ol>		

### 7.3 QFN32 Package Marking



Figure 7.3. QFN32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
aaa	0.20		
bbb	0.20		
ccc	0.10		
ddd	0.20		
theta	0°	3.5°	7°
<b>Note:</b> <ol style="list-style-type: none"> <li>1. All dimensions shown are in millimeters (mm) unless otherwise noted.</li> <li>2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.</li> <li>3. This drawing conforms to JEDEC outline MS-026.</li> <li>4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.</li> </ol>			

### 8.3 QFP32 Package Marking

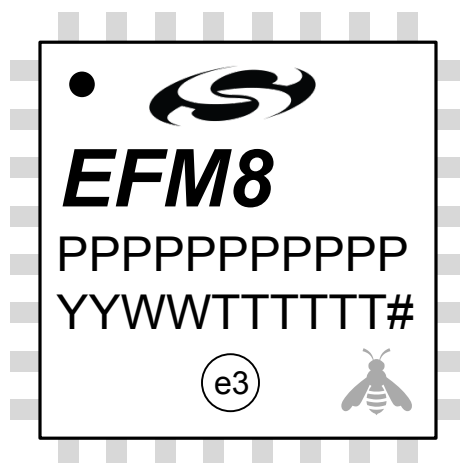


Figure 8.3. QFP32 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Typ	Max
e	0.40 BSC		
e1	0.45 BSC		
J	1.60	1.70	1.80
K	1.60	1.70	1.80
L	0.35	0.40	0.45
L1	0.25	0.30	0.35
aaa	—	0.10	—
bbb	—	0.10	—
ccc	—	0.08	—
ddd	—	0.1	—
eee	—	0.1	—

**Note:**

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-248 but includes custom features which are toleranced per supplier designation.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

### 10.3 QSOP24 Package Marking



Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- P P P P P P P P – The part number designation.
- T T T T T T – A trace or manufacturing code.
- Y Y – The last 2 digits of the assembly year.
- W W – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).